

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)		ATTY. DOCKET NO. 60188-807		SERIAL NO.			
		APPLICANT Osamu KUSUMOTO, et al.					
		FILING DATE March 17, 2004		GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codez (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
SR		JP 11-297712	10/29/1999	SANYO ELECTRIC CO LTD		Yes	No
SR		JP P2002-93742A	03/29/2002	NATIONAL INSTITUTE OF ADVANCED INDUSTRIAL & TECHNOLOGY NISSAN MOTOR CO LTD		(Japan w/English Abstract)	
SR		JP 10-125620	05/15/1998	DENSO CORP		(Japan w/English Abstract)	
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
SR		Toshiyuki OHNO, "Recent Progress in SiC-Based Device Processing", Journal of Institute of Electronics, Information and Communication Engineers, pp. 128-133, Vol. J81-C-II, No. 1, January 1998, Japan					
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EXAMINER		DATE CONSIDERED					
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<i>Spl</i>		<p style="text-align: center;">PARTIAL ENGLISH TRANSLATION OF:</p> <p style="text-align: center;">Toshiyuki OHNO, "Recent Progress in SiC-Based Device Processing", Journal of Institute of Electronics, Information and Communication Engineers, pp. 128-133, Vol. J81-C-II, No. 1, January 1998, Japan</p>	

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